

Functional Safety Information

TPS6281x

Functional Safety FIT Rate, FMD and Pin FMA



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1 Overview

This document contains information for TPS62810, TPS62811, TPS62812, and TPS62813 (VQFN package) to aid in a functional safety system design. Information provided are:

- Functional safety failure in time (FIT) rates of the semiconductor component estimated by the application of industry reliability standards
- Component failure modes and distribution (FMD) based on the primary function of the device
- Pin failure mode analysis (Pin FMA)

Figure 1-1 shows the device functional block diagram for reference.

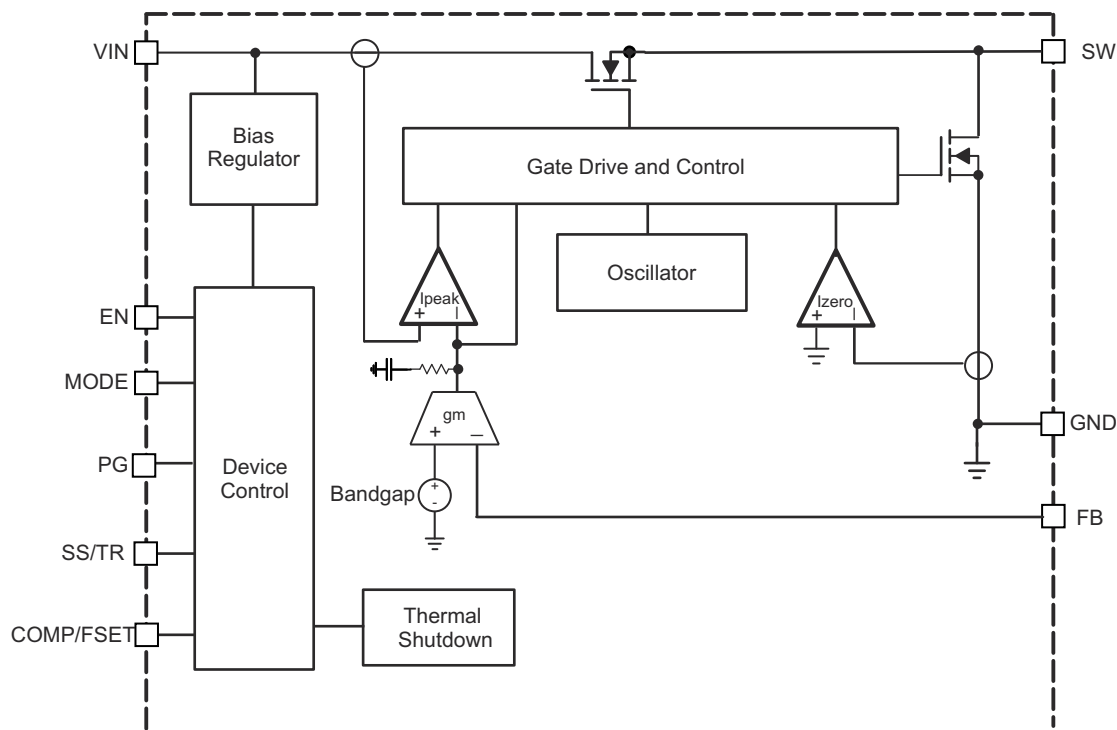


Figure 1-1. Functional Block Diagram

TPS6281x were developed using a quality-managed development process, but were not developed in accordance with the IEC 61508 or ISO 26262 standards.

2 Functional Safety Failure In Time (FIT) Rates

This section provides functional safety failure in time (FIT) rates for TPS6281x based on two different industry-wide used reliability standards:

- [Table 2-1](#) provides FIT rates based on IEC TR 62380 / ISO 26262 part 11.
- [Table 2-2](#) provides FIT rates based on the Siemens Norm SN 29500-2.

Table 2-1. Component Failure Rates per IEC TR 62380 / ISO 26262 Part 11

FIT IEC TR 62380 / ISO 26262	FIT (Failures Per 10 ⁹ Hours)
Total component FIT rate	9
Die FIT rate	5
Package FIT rate	4

The failure rate and mission profile information in [Table 2-1](#) comes from the reliability data handbook IEC TR 62380 / ISO 26262 part 11:

- Mission profile: Motor control from table 11 or figure 16
- Power dissipation: 500mW
- Climate type: World-wide table 8 or figure 13
- Package factor (lambda 3): From table 17b or figure 15
- Substrate material: FR4
- EOS FIT rate assumed: 0 FIT

Table 2-2. Component Failure Rates per Siemens Norm SN 29500-2

Table	Category	Reference FIT Rate	Reference Virtual T _J
5	CMOS, BICMOS Digital, analog or mixed	25 FIT	55 °C

The reference FIT rate and reference virtual T_J (junction temperature) in [Table 2-2](#) come from the Siemens Norm SN 29500-2 tables 1 through 5. Failure rates under operating conditions are calculated from the reference failure rate and virtual junction temperature using conversion information in SN 29500-2 section 4.

3 Failure Mode Distribution (FMD)

The failure mode distribution estimation for TPS6281x in [Table 3-1](#) comes from the combination of common failure modes listed in standards such as IEC 61508 and ISO 26262, the ratio of sub-circuit function size and complexity, and from best engineering judgment.

The failure modes listed in this section reflect random failure events and do not include failures resulting from misuse or overstress.

Table 3-1. Die Failure Modes and Distribution

Die Failure Modes	Failure Mode Distribution (%)
SW no output	35
SW output not in specification – voltage or timing	45
SW power HS or LS FET stuck on	10
PG false trip or fails to trip	5
Short circuit any two pins	5

4 Pin Failure Mode Analysis (Pin FMA)

This section provides a failure mode analysis (FMA) for the pins of the TPS6281x. The failure modes covered in this document include the typical pin-by-pin failure scenarios:

- Pin short-circuited to ground (see [Table 4-2](#))
- Pin open-circuited (see [Table 4-3](#))
- Pin short-circuited to an adjacent pin (see [Table 4-4](#))
- Pin short-circuited to VIN (see [Table 4-5](#))

[Table 4-2](#) through [Table 4-5](#) also indicate how these pin conditions can affect the device as per the failure effects classification in [Table 4-1](#).

Table 4-1. TI Classification of Failure Effects

Class	Failure Effects
A	Potential device damage that affects functionality.
B	No device damage, but loss of functionality.
C	No device damage, but performance degradation.
D	No device damage, no impact to functionality or performance.

[Figure 4-1](#) shows the TPS6281x pin diagram for the VQFN package. For a detailed description of the device pins, see the *Pin Configuration and Functions* section in the TPS6281x datasheet.

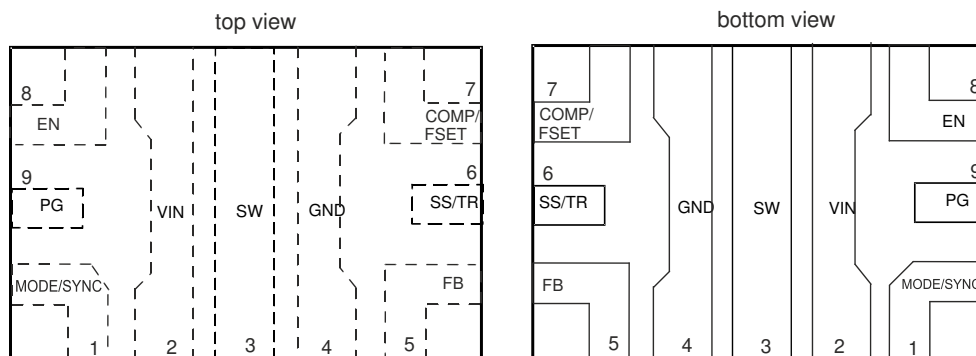


Figure 4-1. Pin Diagram

Following are the assumptions of use and the device configuration assumed for the pin FMA in this section:

- The device is used according to the typical application, refer to the *Simplified Schematics* section in the TPS6281x datasheet.

Table 4-2. Pin FMA for Device Pins Short-Circuited to Ground

Pin Name	Pin No.	Description of Potential Failure Effects	Failure Effect Class
MODE/SYNC	1	The device functions as intended.	D
VIN	2	The device does not power up.	B
SW	3	The device is potentially damages.	A
GND	4	There is no effect to the device.	D
FB	5	The output voltage is regulated to V_{IN} (100% mode).	B
SS/TR	6	The device is not functional.	B
COMP/FSET	7	The device functions as intended.	D
EN	8	The device functions as intended.	D
PG	9	The device functions as intended.	D

Table 4-3. Pin FMA for Device Pins Open-Circuited

Pin Name	Pin No.	Description of Potential Failure Effects	Failure Effect Class
MODE/SYNC	1	The operation of the device is undetermined.	B
VIN	2	The device does not power up.	B
SW	3	The device is not functional, open loop operation.	B
GND	4	The device is not functional.	B
FB	5	The output voltage behavior is undetermined; open loop operation.	B
SS/TR	6	The device functions as intended.	D
COMP/FSET	7	The device functions as intended.	D
EN	8	The operation of the device is undetermined; the device potentially power up or potentially does not power up.	B
PG	9	The device functions as intended.	B

Table 4-4. Pin FMA for Device Pins Short-Circuited to Adjacent Pin

Pin Name	Pin No.	Shorted to	Description of Potential Failure Effects	Failure Effect Class
MODE/SYNC	1	PG	The device runs FPWM mode once the PG pin is high impedance.	B
FB	5	SS/TR	The operation of the device is undetermined, V_{OUT} spikes up to V_{IN} .	B
SS/TR	6	COMP/FSET	The operation of the device is undetermined.	B
EN	8	PG	The device does not power up.	B

Table 4-5. Pin FMA for Device Pins Short-Circuited to VIN

Pin Name	Pin No.	Description of Potential Failure Effects	Failure Effect Class
MODE/SYNC	1	The device functions as intended: Forced PWM.	D
VIN	2	The device functions as intended.	D
SW	3	The device is potentially damaged.	A
GND	4	The device does not power up.	B
FB	5	The device is potentially damaged.	A
SS/TR	6	The device functions as intended.	D
COMP/FSET	7	The device functions as intended.	D
EN	8	The device functions as intended.	D
PG	9	The device is potentially damaged.	A

5 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
June 2026	*	Initial Release

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